24 🛮 V<sub>CC</sub>

23 Y1

22 Y2

21 Y3

18 Y6

17 Y Y7

16**∏** Y8

15 Y9

14**∏** Y10

13 OE2

20 1 y4 19 Y5

DW OR NT PACKAGE

(TOP VIEW)

OE1

Α1 2

A2 **3** 

Α4 5

Α7 8

Α9

A10

A8 🛮 9

10

11 GND 1 12

АЗ [

A5 🛮 П A6

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- Functionally Equivalent to AMD's AM29827 and AM29828
- 3-State Outputs Drive Bus Lines or Buffer **Memory Address Registers**
- pnp Inputs Reduce dc Loading
- Data Flow-Through Pinout (All Inputs on **Opposite Side From Outputs)**
- Power-Up High-Impedance State
- **Package Options Include Plastic** Small-Outline (DW) Packages and Standard Plastic (NT) 300-mil DIPs

# description

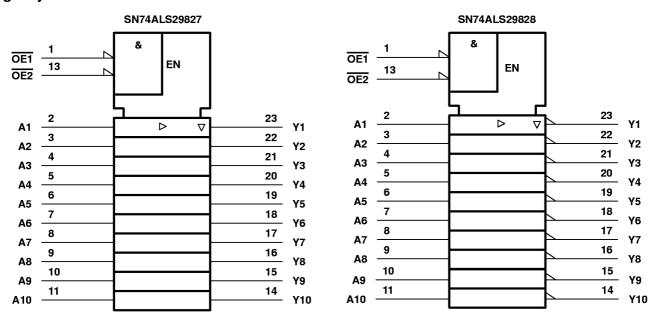
These 10-bit buffers and bus drivers provide high-performance bus interface for wide data paths or buses carrying parity.

The 3-state control gate is a 2-input NOR such that if either output-enable ( $\overline{OE1}$  or  $\overline{OE2}$ ) input is high, all ten outputs are in the high-impedance state.

The SN74ALS29827 provides true data and the SN74ALS29828 provides inverted data at their respective outputs.

The SN74ALS29827 and SN74ALS29828 are characterized for operation from 0°C to 70°C.

# logic symbols†

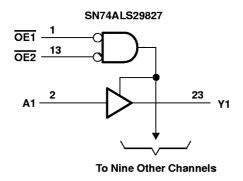


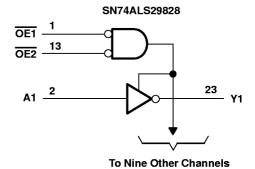
<sup>†</sup>These symbols are in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.



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# logic diagrams (positive logic)





# absolute maximum ratings over operating free-air temperature range (unless otherwise noted)†

Supply voltage, V <sub>CC</sub>	7 V
Input voltage, V <sub>I</sub>	5.5 V
Voltage applied to a disabled 3-state output	5.5 V
Operating free-air temperature range, T <sub>A</sub>	$\dots$ 0°C to 70°C
Storage temperature range	-65°C to 150°C

<sup>†</sup> Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

### recommended operating conditions

		SN74ALS29827 SN74ALS29828		UNIT	
		MIN	NOM	MAX	
Vcc	Supply voltage	4.75	5	5.25	٧
$V_{IH}$	High-level input voltage	2			V
VIL	Low-level input voltage			8.0	٧
ІОН	High-level output current			-24	mA
loL	Low-level output current			48	mA
TA	Operating free-air temperature	0		70	°C

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# electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER	TEST COI	TEST CONDITIONS		SN74ALS29827 SN74ALS29828		
				TYPT	MAX	
V <sub>IK</sub>	$V_{CC} = 4.75 V$ ,	I <sub>I</sub> = −18 mA			-1.2	V
Vou	V <sub>CC</sub> = 4.75 V	I <sub>OH</sub> = -15 mA	2.4			V
Voн		$I_{OH} = -24 \text{ mA}$	2			V
V <sub>OL</sub>	$V_{CC} = 4.75 V$ ,	$I_{OL} = 48 \text{ mA}$		0.35	0.5	V
lozн	$V_{CC} = 5.25 V$ ,	V <sub>O</sub> = 2.4 V			20	μΑ
<sup>l</sup> OZL	$V_{CC} = 5.25 V$ ,	V <sub>O</sub> = 0.4 V			-20	μΑ
IJ	$V_{CC} = 5.25 V$ ,	V <sub>I</sub> = 5.5 V			0.1	mA
lн	$V_{CC} = 5.25 V$ ,	V <sub>I</sub> = 2.7 V			20	μА
IIL	$V_{CC} = 5.25 V$ ,	V <sub>I</sub> = 0.4 V			-0.1	mA
los <sup>‡</sup>	$V_{CC} = 5.25 V$ ,	V <sub>O</sub> = 0	-75		-250	mA
lcc	V <sub>CC</sub> = 5.25 V			25	40	mA

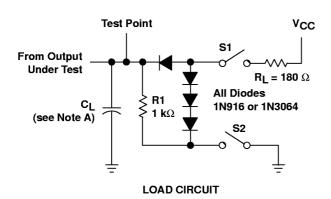
<sup>†</sup> All typical values are at  $V_{CC} = 5 \text{ V}$ ,  $T_A = 25^{\circ}\text{C}$ .

# switching characteristics (see Figure 1)

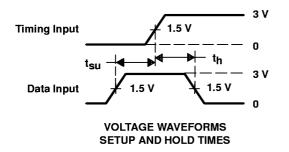
	FROM	FROM TO TEST CONDITION			V to 5.25 V	
PARAMETER			TIEST CONDITIONS LSN/4AL	SN74ALS29827	SN74ALS29828	UNIT
	(1141 01)			MIN MAX	MIN MAX	
<sup>t</sup> PLH	А	V	0 000 5	15	14	ns
<sup>t</sup> PHL	*	Υ	C <sub>L</sub> = 300 pF	15	14	115
<sup>t</sup> PLH	А	Y	0 50 5	8	7	ns
<sup>t</sup> PHL	ζ .	Y	C <sub>L</sub> = 50 pF	8	7.5	20
<sup>t</sup> PZH	Œ	Υ	0 000 5	20	20	ns
<sup>t</sup> PZL	OE	Y	C <sub>L</sub> = 300 pF	23	23	10
<sup>t</sup> PZH	Œ	V	C 50 - 5	15	15	ns
<sup>t</sup> PZL		Y	C <sub>L</sub> = 50 pF	15	15	115
<sup>t</sup> PHZ	ŌĒ	V	0 50 5	17	17	ns
tPLZ	OE	Y C <sub>L</sub> = 5	C <sub>L</sub> = 50 pF	12	12	115
<sup>t</sup> PHZ	ŌĒ	Y	C <sub>L</sub> = 5 pF	9	9	ns
<sup>t</sup> PLZ	JE JE	f	OL = 2 pr	9	9	115

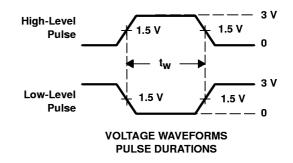
<sup>‡</sup> Not more than one output should be shorted at a time, and the duration of the short circuit should not exceed one second.

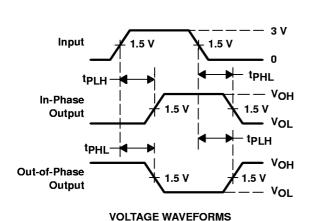
#### PARAMETER MEASUREMENT INFORMATION



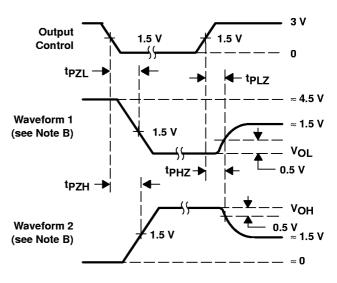
SWITCH POSITION TABLE				
TEST	S1	S2		
tPLH tPHL tPZH tPZL tPHZ tPHZ	Closed Closed Open Closed Closed Closed	Closed Closed Closed Open Closed Closed		







**PROPAGATION DELAY TIMES** 



VOLTAGE WAVEFORMS
ENABLE AND DISABLE TIMES, 3-STATE OUTPUTS

NOTES: A. C<sub>L</sub> includes probe and jig capacitance.

- B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control.

  Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
- C. All input pulses are supplied by generators having the following characteristics: PRR  $\leq$  10 MHz,  $Z_O = 50 \Omega$ ,  $t_f \leq 2.5$  ns.  $t_f \leq 2.5$  ns.

Figure 1. Load Circuit and Voltage Waveforms



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